Electronic Supplementary Material (ESI) for Journal of Materials Chemistry A.

Electronic supplementary information

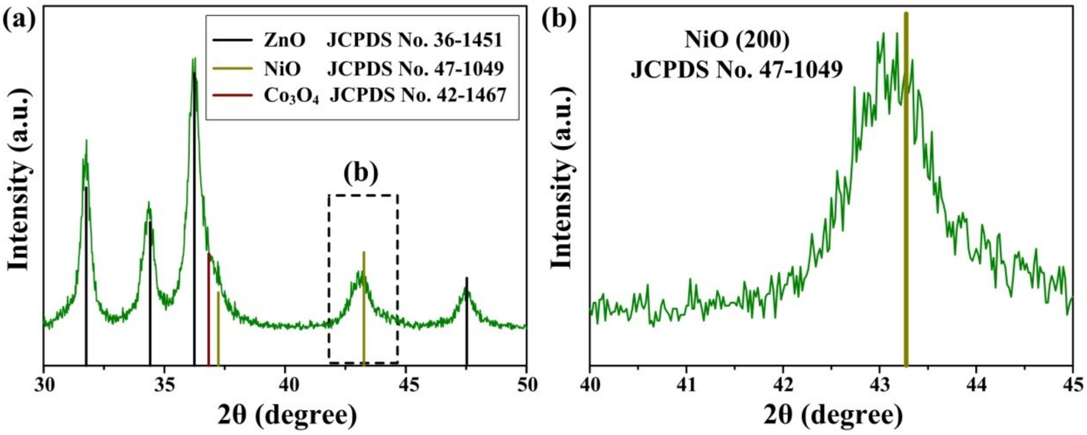
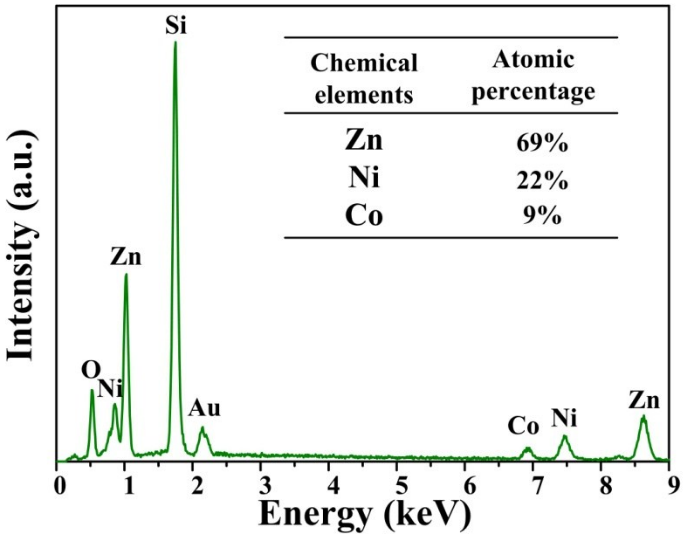


Fig. S1 (a) Part of the XRD pattern of ZNC NFs and corresponding standard JCPDS cards, (b) the enlarged pattern of the region marked by black rectangle in (a).



Chemical elements	Atomic percentage
Zn	69%
Ni	22%
Co	9%

Fig. S2 EDS analysis of ZNC NFs and the corresponding atomic percentages of Zn, Ni and Co. The samples were dispersed on Si substrates and gold-sprayed prior to FESEM and EDS measurements, thus Si and Au were also detected as shown in Fig. S2.

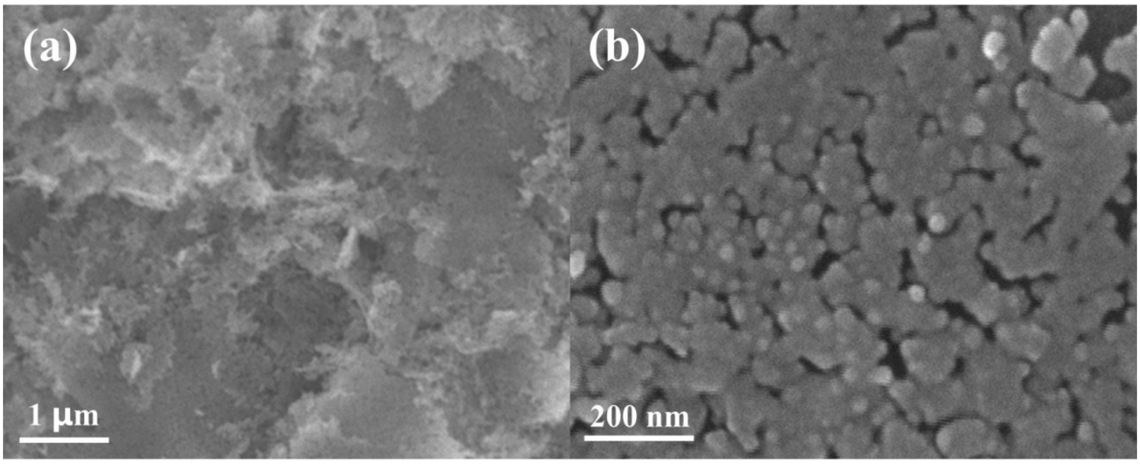


Fig. S3 (a) Low and (b) high magnification FESEM images of ZN NFs

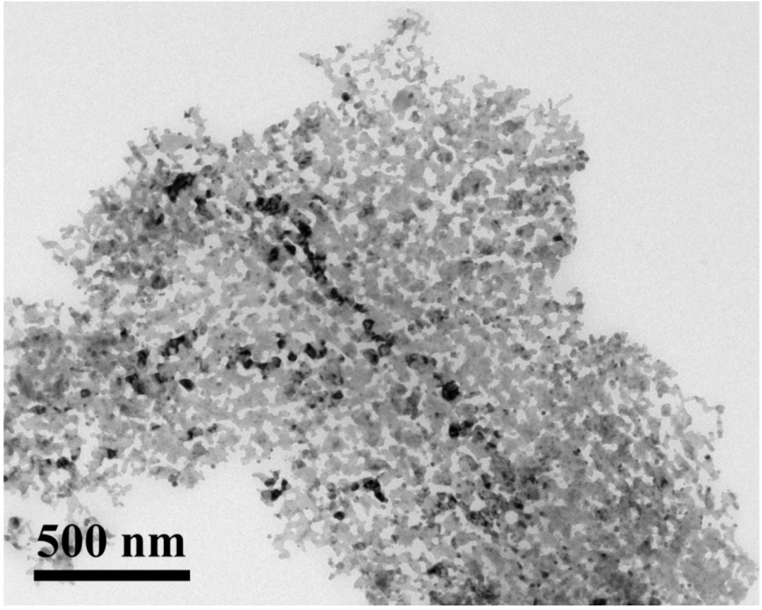


Fig. S4 TEM image of a single ZnO-NiO@Co_3O_4 nanoflake, which is used to measure the average particle size of ZnO and NiO.

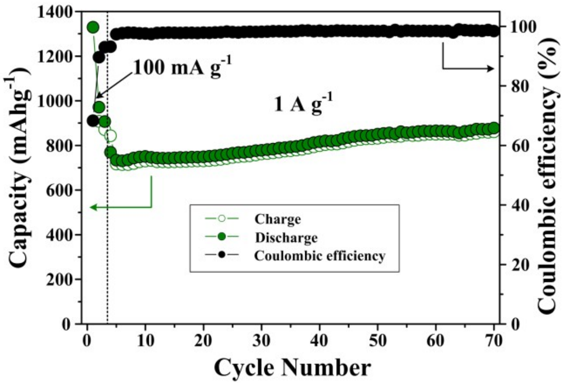


Fig. S5 Cycling performance of ZNC NFs at 1 A g^{-1}.